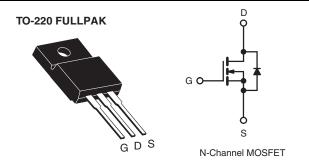


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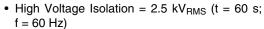
Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	60			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.028		
Q _g (Max.) (nC)	95			
Q _{gs} (nC)	27			
Q _{gd} (nC)	46			
Configuration	Single			



FEATURES







COMPLIANT

• Sink to Lead Creepage Distance = 4.8 mm

- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The molding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. The isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION			
Package	TO-220 FULLPAK		
Lead (Pb)-free	IRFIZ44GPbF		
Lead (PD)-liee	SiHFIZ44G-E3		
SnPb	IRFIZ44G		
SILD	SiHFIZ44G		

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	60	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D	30	А	
		T _C = 100 °C		21		
Pulsed Drain Current ^a			I _{DM}	120		
Linear Derating Factor				0.32	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	100	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	48	W	
Peak Diode Recovery dV/dtc			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		· ·	300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 129 \,\mu\text{H}$, $R_G = 25 \,\Omega$, $I_{AS} = 30 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le 52$ A, $dI/dt \le 250$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFIZ44G, SiHFIZ44G

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.1	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	60	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	-	0.060	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zava Cata Valtana Duain Cumant		V _{DS} = 60 V, V _{GS} = 0 V		-	-	25	ι. Λ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 48 V	V _{GS} = 0 V, T _J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 18 A ^b	-	-	0.028	Ω
Forward Transconductance	9 _{fs}	V _{DS} :	= 25 V, I _D = 18 A ^b	15	-	-	S
Dynamic		•					
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	2500	-	-
Output Capacitance	C _{oss}	1	$V_{DS} = 25 \text{ V},$		1200	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5 f = 1.0 MHz		-	200	-	pF
Drain to Sink Capacitance	С			-	12	-	
Total Gate Charge	Qg		I _D = 52 A, V _{DS} = 48 V, see fig. 6 and 13 ^b	-	-	95	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	27	
Gate-Drain Charge	Q _{gd}	7		-	-	46	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 30 \text{ V}, I_{D} = 52 \text{ A},$ $R_{G} = 9.1 \Omega, R_{D} = 0.54 \Omega,$ see fig. 10^{b}		-	19	-	- ns
Rise Time	t _r			-	120	-	
Turn-Off Delay Time	t _{d(off)}			-	55	-	
Fall Time	t _f			-	86	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s			•			,
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	30	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	120	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 30 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	2.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 52 A, dl/dt = 100 A/μs ^b		-	140	300	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.2	2.8	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	n-on is dominated by L _S and L _D)				

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

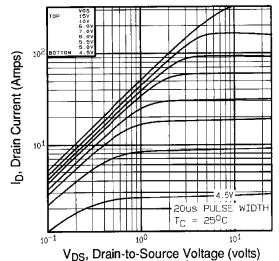


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

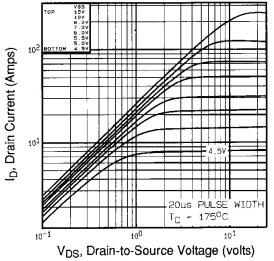


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

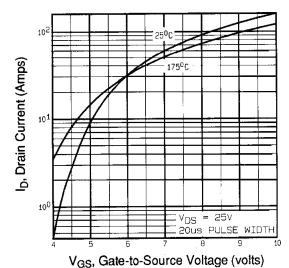


Fig. 3 - Typical Transfer Characteristics

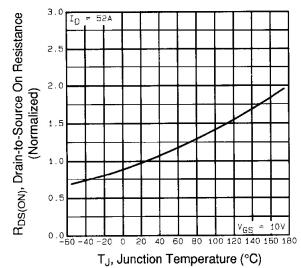


Fig. 4 - Normalized On-Resistance vs. Temperature

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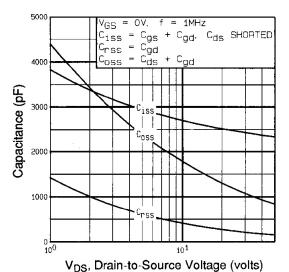


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

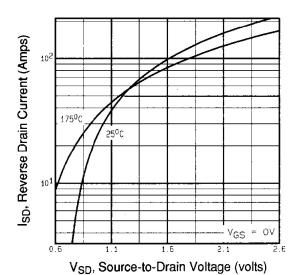


Fig. 7 - Typical Source-Drain Diode Forward Voltage

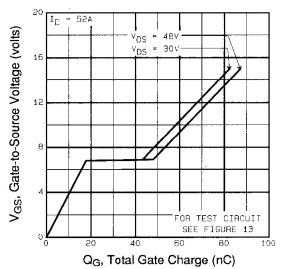
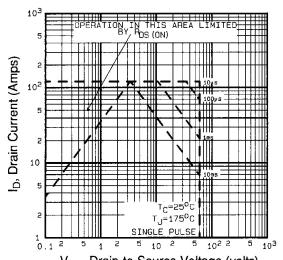


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



 V_{DS} , Drain-to-Source Voltage (volts) Fig. 8 - Maximum Safe Operating Area



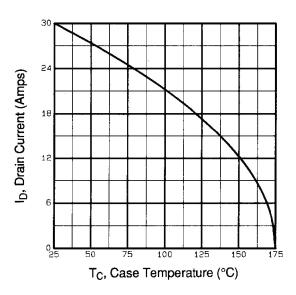


Fig. 9 - Maximum Drain Current vs. Case Temperature

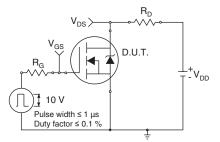


Fig. 10a - Switching Time Test Circuit

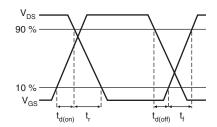


Fig. 10b - Switching Time Waveforms

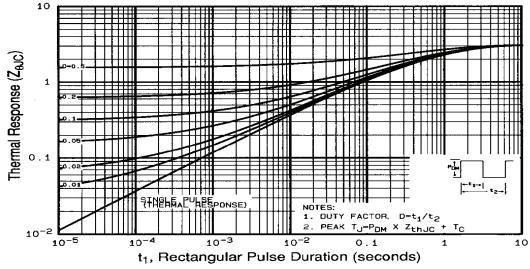


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

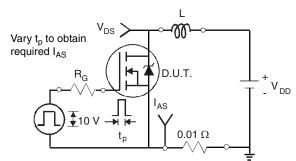


Fig. 12a - Unclamped Inductive Test Circuit

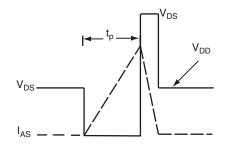
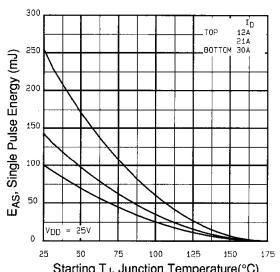


Fig. 12b - Unclamped Inductive Waveforms

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 $Starting \ T_J, \ Junction \ Temperature (^{\circ}C)$ Fig. 12c - Maximum Avalanche Energy vs. Drain Current

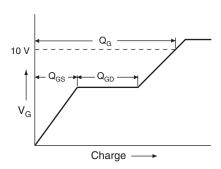


Fig. 13a - Basic Gate Charge Waveform

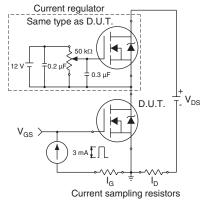
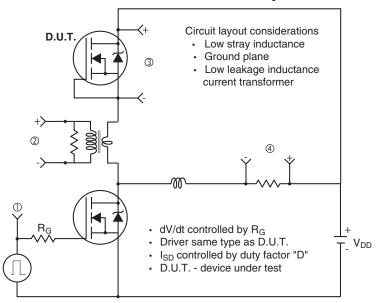
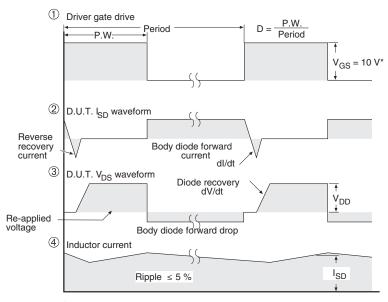


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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